Tektronix[®]

Automotive Ethernet MultiGBASE-T1, 1000BASE-T1 and 100BASE-T1 Compliance

DPO70000SX/DX AUTOEN10G and BRR Option Datasheet



The Tektronix Option AUTOEN10G (MultiGBASE-T1) and BRR (100BASE-T1/1000BASE-T1) applications provide the most comprehensive solution for Automotive Ethernet transmitter compliance testing as well as debug and validation of Automotive Ethernet devices and ECUs against the IEEE and Open Alliance specifications. These options are available on MSO/DPO70000DX and DPO70000SX Series oscilloscopes.

Features and Benefits

Test coverage: All transmitter compliance tests for 100BASE-T1 (IEEE 802.3bw), 1000BASE-T1 (IEEE 802.3bp) and MultiGBASE-T1 (IEEE 802.3ch) are available through a single Automotive Ethernet compliance application. The application uses the TekExpress automation framework and tests as per IEEE and Open Alliance specification for Tektronix DPO70000 SX/DX oscilloscopes.

Test time: Fully automated with setup wizard, configures all required test parameters to perform compliance testing as per Automotive Ethernet standards. Highly optimized and intuitive user interface for quick test configuration and validation of electrical signals.

Accuracy: The application runs on Tektronix DPO70000 SX/DX Series oscilloscopes for accurate and repeatable results.

Pattern matching: Verifies that the correct set of compliance patterns are sent by the transmitter before acquiring signals for compliance analysis.

Reporting: Compiles all test results into a customizable report with Pass/Fail results for easy analysis and record keeping, as well as margin testing.

Compliance and debug: Provides a toolkit of DPOJET-based setups to quickly switch into debug and validation mode when a DUT fails compliance.

Analysis and debug tools: Supporting tools, such as TekExpress User defined Mode, advanced DPOJET jitter analysis (Otp. DJA), PAM4 Eye Diagram Analysis (Opt PAM4) tools help to catch problems before compliance testing, or root-cause the problem in the event of a failure.

Performance verification: The Automotive Ethernet application allows you to run a test multiple times and save or stop acquisitions in the event of an out-of-limit condition. The report shows statistics with pass/ fail results for each run to show device performance over multiple runs.

PHY level protocol decode: SR-AUTOETH1 option decodes and displays the 100BASE-T1 data in a protocol-aware view. A time-correlated event table view with waveforms allows for quickly searching through events of interest.

Comprehensive programmatic interface: Enables automation programs and scripts to call Automotive Ethernet test functions.

Automated Automotive Ethernet compliance application

Physical layer compliance tests have been defined to ensure interoperability between different designs and hardware vendors. Tektronix Automotive Ethernet compliance testing application provides the most comprehensive solution to serve the needs of engineers designing Automotive Ethernet silicon or electronic control units (ECUs), as well as those validating physical layer compliance of Automotive Ethernet as per IEEE or Open Alliance specifications.

	10BASE- T1S	100BASE- T1	1000BASE -T1S	MultiGBA SE-T1
IEE Spec	802.3cg	802.3bw	802.3bp	802.3ch
Open Alliance ECU Spec	TC8			
Datarate	10 Mbps	100 Mbps	1 Gbps	2.5/5/10 Gbps
Symbol rate	12.5 MHz	66.66 MHz	750 MHz	1.4/2.8/5.6 GHz
Line coding	4B/5B, DME	PAM3	PAM3	PAM4
Voltage	1 Vpp	2.2 Vpp	1.3 Vpp	1.3 Vpp
Communication	Half Duplex	Full Duplex	Full Duplex	Full Duplex

Industry defined testing for Automotive Ethernet

The IEEE and Open Alliance provide compliance tests for an Automotive Ethernet PHY or ECU. As per the IEEE and Open Alliance, we have the following compliance requirements for Physical Media Attachment (PMA) transmitter test for an Automotive Ethernet PHY or ECU.

Test Name	100BASE- T1 IEEE 802.3 bw	ECU TC8 100/1000B ASE-T1	1000BASE -T1 IEEE 802.3 bp	MultiGBA SE-T1 IEEE 802.3 ch
Transmitter output Droop	96.5.4.1	OABR_PM A_TX_01	97.5.3.1	149.5.2.1
Transmitter Distortion	96.5.4.2	OABR_PM A_TX_08	97.5.3.2	NA
Transmitter Linearity	NA	NA	NA	149.5.2.2
Transmitter Timing Jitter in Master/Slave Mode	96.5.4.3	OABR_PM A_TX_02	97.5.3.3	149.5.2.3

Test Name	100BASE- T1 IEEE 802.3 bw	ECU TC8 100/1000B ASE-T1	1000BASE -T1 IEEE 802.3 bp	MultiGBA SE-T1 IEEE 802.3 ch
Transmitter MDI Jitter	NA	NA	97.5.3.3	NA
Tx MDI Random Jitter (Master)	NA	NA	NA	149.5.2.3. 1
Tx MDI Deterministic Jitter (Master)	NA	NA	NA	149.5.2.3. 2
Transmitter Power Spectral Density (PSD)	96.5.4.4	OABR_PM A_TX_04	97.5.3.4	149.5.2.4
Transmit Clock Frequency	96.5.6	OABR_PM A_TX_03	97.5.3.6	149.5.2.6
Transmitter Peak Differential Output	96.5.4.5	NA	97.5.3.5	149.5.2.5
MDI Return Loss	96.8.2.1	OABR_PM A_TX_05	97.7.2.1	149.8.2.1
MDI Mode Conversion	NA	OABR_PM A_TX_06	NA	NA
Common Mode Emission	NA	Only 100BASE- T1	NA	NA

Each test requires the engineer to set the required test mode, acquire waveforms with the correct instrument settings, and analyze the results per the standard. Manually capturing and analyzing them is tedious, time consuming, and subject to errors.

The TekExpress Automotive Ethernet compliance application allows you to automatically execute physical layer electrical tests for transmitter compliance using IEEE and/or Open Alliance (OABR) specifications. The Tektronix Option BRR and AUTOEN10G applications combine to form a TekExpress[™] compliance automation solution for 100BASE-T1, 1000BASE-T1 and MultiGBASE-T1 Automotive Ethernet with a single user interface. The TekExpress Automotive Ethernet application is configured by following a step-by-step process. The application sets up the oscilloscope and automates testing, guiding you to accurate and repeatable results.

MultiGBASE-T1 PMA Transmitter Compliance Measurements

MultiGBASE-T1 is specified in IEEE 802.3ch, an extension to BASE-T1 PHYs at speeds in excess of 1000 Mb/s, including 2.5GBASE-T1, 5GBASE-T1, and 10GBASE-T1. The physical layer operates over a

single pair of shielded cable in full-duplex mode with four level pulse amplitude modulation (PAM4).

MultiGBASE-T1 PMA Transmitter Measurements

Test Spec	Test Mode	Pattern Type	Instrument
Tx Output Droop	6		Oscilloscope
Tx Linearity	4	PAM4	Oscilloscope
Tx Timing Jitter (Master and Slave)	1	Clock	Oscilloscope
Tx MDI Random Jitter (Master Mode)	2	Square	Oscilloscope
Tx MDI Deterministic Jitter (Master Mode)	2	JP03A	Oscilloscope
Even Odd Jitter (EOJ)	2	JP03B	Oscilloscope
Tx Power Spectral Density and Power level	5	PAM4	Oscilloscope
Tx Clock Frequency	1	Clock	Oscilloscope
Tx Peak Differential Output	5	PAM4	Oscilloscope
MDI Return Loss	Slave		VNA

1000BASE-T1 PMA Transmitter Measurements:

Test Spec	Test Mode	Pattern Type	Instrument
Tx Output Droop	6		Oscilloscope
Tx Distortion	4	PAM3	Oscilloscope
Tx Timing Jitter (Master and Slave)	1	Clock	Oscilloscope
Tx MDI Jitter	2	Clock	Oscilloscope
Tx Power Spectral Density and Power level	5	PAM3	Oscilloscope
Tx Clock Frequency	1	Clock	Oscilloscope
Tx Peak Differential Output	5	PAM3	Oscilloscope

Test Spec	Test Mode	Pattern Type	Instrument
MDI Return Loss	Slave		Vector Network Analyzer or Oscilloscope + AWG
MDI Mode Conversion	Slave		VNA

Test Spec	Test Mode	Pattern Type	Instrument
Tx Output Droop	6		Oscilloscope
Tx Distortion	4	PAM4	Oscilloscope
Tx Timing Jitter (Master and Slave)	1	Clock	Oscilloscope
Tx Power Spectral Density and Power level	5	PAM3	Oscilloscope
Tx Clock Frequency	2	Clock	Oscilloscope
Tx Peak Differential Output	5	PAM3	Oscilloscope
MDI Return Loss	Slave		VNA
MDI Mode Conversion	Slave		VNA
MDI Common Mode Emission	5	PAM3	Oscilloscope

100BASE-T1 PMA Transmitter Measurements:

The TekExpress Automotive Ethernet Automated Testing Application

The Tektronix Automotive Ethernet application offers exceptional ease of use with the TekExpress Automation platform. Testing follows a logical workflow for quick, easy test setups, changes and review of test results. Valid testing requires proper cabling, probes, and connections between fixtures, instruments, and the device under test (DUT). The application provides setup instructions for each test, with images and reference illustrations showing correct configurations. It generates a comprehensive, date-stamped test report with pass/fail results, waveforms, and data plots.

Accurate, repeatable compliance tests follow a 5-step workflow.

Step 1: Selection of Test Suite

Setup 1 DUT DUT ID DUTIO1 Image: Constraint of the set of the s	TekExpress Automotive Ethe	ernet - (Untitled)*	Options
V 50Base-T1 V 10GBase-T1 Probing Type ○ Differential Single-Ended	Setup Status Results Plots Reports	DUTID DUT01 (2) Acquire live waveforms Use pre-recorded waveform files Suite MultiGBase-T1 Use pre-recorded waveform files 1000Base-T1 EE P802.3ch™ DataR MultiGBase-T1 EE P802.3ch™ DataR MultiGBase-T1 V 5GBase-T1 V 5GBase-T1 V forgase-T1 O Differential Single-Ended	Pause

Figure 1: Automotive Ethernet Test suit selection

Test selections include Automotive Ethernet 100BASE-T1, 1000BASE-T1 and MultiGBASE-T1. You can select different speed gears for MultiGBASE-T1. The test selection, test limits and configuration will be selected based on the test suite selected. You can test using live oscilloscope waveforms or previously recorded waveforms or sessions.

Step 2: Test Selection



Figure 2: Automotive Ethernet MultiGBASE-T1 Test selection

Based on the test suite selection in Step 1, the TekExpress Automotive Ethernet application allows you to select one or multiple tests from the test tree for the respective test suite.

Schematic views and descriptions guide you through connections, along with test information and golden waveforms. If you select multiple

tests, the application will provide prompts to set the correct DUT test mode and make the appropriate connections.



Figure 3: Automotive Ethernet 1000BASE-T1 Test selection



Note: For best resuts, connect the oscilloscope, DUT and test fixtures to a common ground

Figure 4: Schematic view

Step 3: Selection Acquisition and Signal Validation



Figure 5: Signal Acquisition and Validation

It is important to validate the signal parameters before performing compliance test. The TekExpress application checks for the correct test mode waveform before running any test. This ensures that the proper test connections are in place and that the DUT is sending the appropriate test pattern.

Step 4: Configuration of User-defined and Compliance Mode

🏑 TekExpress Automotive Eth	ernet - (Untitled)*	Options 💌	
Setup DUT	Compliance Mode OUser Defined Mode	Limits	Start
Status V Test Selection	Global Settings Measurements Calibration		
Results Acquisitions	Transmitter Clock Frequency Test Mode 4 Transmitter Linearity Test Mode 5	^	Pause
Plots 4 Configuration	Transmitter Power Spectral Density and Power Level Transmitter Peak Differential Output		
Reports 5 Preferences	E-Test Mode 6 Maximum Output Droop E-Slave Idle Mode ↓ MDI Return Loss	*	
	10GBase-T1		
	Acquire RBW KHz		
	Analyze Start Frequency 0 MHz		
	Stop Frequency 5500 MHz		
Completed.			

Figure 6: User defined configuration for PSD test

The application allows you to configure the test in Compliance Mode or User-defined Mode. In Compliance Mode, the application configures the oscilloscope per the test procedure defined in the test specifications from the applicable standard. The DUT is tested against limits defined by the standard. In User-defined Mode, you can change the oscilloscope parameters such as record length, sample rate, etc., as well as test limits. Userdefined Mode allows you to test your device beyond compliance.

Step 5: Preferences

V TekExpress Automotive Ethe Setup Status Results Piots Reports Preferences	Number of Runs 100 times Number of Runs 100 times Save data for initial 10 set of ALL trials FALL FALL trials Cons on Test Measurement Fallur ALL Email On Test Fallure, stop and notify me of the failure Email Logging Options Fable Logging Hide schematic popup while running the test (for single test selection of the failure schematic popus while running the test selection of the failure schematic popus while running the test (for single test selection of the failure schematic popus while running the test (for single test selection of the failure schematic popus while running the test (for single test selection of the failure schematic popus while running the test (for single test selection of the failure schematic popus while running the test (for single test selection of the failure schematic popus while running the test (for single test selection of the failure schematic popus while running the test (for single test selection of the failure schematic popus while running the test (for single test selection of the failure schematic popus while running the test (for single test selection of the failure schematic popus while running the test (for single test selection of the failure schematic popus while running the test (for single test selection of the failure schematic popus while running the test (for single test selection of the failure schematic popus while running the test (for single test selection of the failure schematic sch	Options Cart
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Figure 7: Multi-run Configuration for Statistical Analysis

The testing application allows you to run multiple consecutive tests for statistical analysis. You can save the waveforms from failed tests for debugging.

Pass/Fail Report:

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Setup Informatio	5n							
DUTID		DUT001		TekExp	ress Automotive	e-Ethernet	10.5.0.171 (BETA)	
Date/Time		2020-11-	26.05:05:24	Framew	ork Version		5 3 0 25	
Pre-Recorded Mr	ode	False		Scopel	lodel		DP073304DX	
Compliance Mor	de	False		Firmwa	re Version		10 12 1 Build 1	
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Dorusting		Lonancin Tan	follive enternation	,				
Test Name Summ	mary Table							
Transmit Even-O	Odd Jitter MDT M	aster Mode		Pass				
Transmit Even-C	Add litter MDI M	aster Mode						
Measurement	2 de la	Tart Saudt	Laure & legalt	Manual Value	Minte Limit	Lunie	ALC: NO	1.0.0
Details	Rate	Test Result	LOW LIMIT	Measured value	High Linn	Units	Margin	Run#
MDI Master Eve							ULANA HI-1	
n-Odd litter P	2.5GBASE-T1	Pass	NA	1.373	16	ps	4.527	1
k-Pk_2.5G							4.027	
MDI Master Eve							LUCK A HILL	
n-Odd litter P	2.5GBASE-T1	Pass	NA	1.327	16	ps	LE N.A. HE I	2
k-Pk_2.5G							4.673	
MDI Master Eve							UL NA HEL	
n-Odd litter P	2.5GBASE-T1	Pass	NA	1.305	16	ps	4.695	3
and prover if						1		1
k-Pk_2.5G	· · · · · · · · · · · · · · · · · · ·							
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I-PL-25C	Sed Jimer MDI M. n-Odd Jitter Re-	2. SCBase-T1 Scope Eandwidth I Run 1: aster Mode PF. 2. SC. Run 1 PF. 2. SC. Run 1 PF. 2. SC. Run 1 Run 1 Run 2 Run 1 Run 1 Run 1 Run 1 Ru				leger of the		k to Sommary Tsi Position 50.0% Factor 17000
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L-PL-2 SG		2. ScBase-TI Scope Bandwidth I Run1: PPL-2. SCI-Bun1 PPL-2. SC	s limited to 4CHz				Eac Address of the second sec	k to Sommary Tsl Postfilon 50.0% Factor 17000

Figure 8: TekExpress Report for MultiGBASE-T1

Creating compliance test documentation is quick and easy in the BRR/ AUTOEN10G application with a summary report in MHL or PDF format. The application generates a report after tests are completed, and includes Pass/Fail status to quickly analyze the test results. The report also includes test configuration details, waveform plots, oscilloscope displays, margin analysis, and statistical analysis to provide insights into your design.

Single Instrument for Time Domain and Frequency Domain Measurements

Automotive Ethernet compliance testing includes time domain measurements like Jitter, Droop, Clock Frequency and Peak Differential Output. It also includes frequency domain measurements such as Power Spectral Density and Return Loss. The Tektronix Automotive Ethernet application allows you to perform all of these measurements using an oscilloscope, eliminating the need to connect a spectrum analyzer or vector network analyzer.

Return Loss Measurement

The MDI return loss test determines the impedance mismatch from the differential impedance specification of 100 Ω , which will affect hardware interoperability. Return loss is a frequency domain measurement, but the Automotive Ethernet application can perform this test with an oscilloscope and function generator using a patented measurement

approach that eliminates the need for additional frequency domain test instruments.



Figure 9: Tektronix Patented Return Loss Measurement using Oscilloscope and AWG for 100/1000BASE-T1



Figure 10: Return Loss plot using Oscilloscope and AWG method

Power Spectral Density

The spectrum of the test signal for the selected standard is computed using oscilloscope math functions. Post processing is done on the signal to arrive at the PSD. The computed PSD is then compared with

the specification by using lower and upper masks to arrive at the final result.



Figure 11: Power Sprectral Density Plot

Analysis and Debug Beyond Compliance

If a DUT fails any portion of the compliance test, powerful debugging and analysis tools such as DPOJET Jitter Analysis, PAM4 Analysis, and protocol decoding are available to determine root cause and examine system-level performance.

DPOJET Jitter Analysis Measurements (required, Option DJA)

The new jitter measurements introduced with MultiGBASE-T1 Ethernet provide separate limits for Deterministic Jitter (DJ), Even Odd Jitter (EOJ) and Random jitter (Rj). The DPOJET Jitter Analysis tool provides additional analysis capabilities like crosstalk and power noise separation to help find the root cause of failures.

Jitter tests quantify the timing variations of the edges of the signal, using specified test patterns. These jitter measurements include the contributions from duty cycle distortion and baseline wander. Jitter is determined by accumulating waveforms and measuring the width of the accumulated points at the eye crossing. The peak-to-peak jitter is inferred from minimum and maximum values in the tails of the histogram.



Figure 12: PAM3 Eye diagram using DPOJET

Apart from jitter measurements for MultiGBASE-T1, DPOJET allows you to perform analysis for following measurements:

- Clock frequency and transmitter amplitude with histogram and trend analysis
- · Positive and negative droop measurements
- Full characterization of jitter performance including TIE and histogram profiles.



Figure 13: Jitter measurement and Analysis using DPOJET

PAM4 Analysis (Option PAM4)

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Mode 1999eV -1185ps 23.92ps 29.97ps 59.97s 17.03ps 14.71ps 17.03ev Lover 49.17ev/ -941.85s 22.42ps 25.57ps 27.73ps 549.91s 13.57ps 21.35ev 150mv/		Upper	73.10m/V	-1.343ps	22.32ps	25.53ps	27.74ps	590.8ts	18.220	a 13.86ps	12.81mV
Lower 49.17m2 441.5ft 22.42pa 25.57ps 27.70ps 547.9ft 18.82ps 13.57ps 21.55m2 Accumulated Eye 150m/f 50m7 0		Middle	1.999mV	-1.186ps	20.58ps	23.69ps	25.77ps	539.9tt	17.03p	s 14.71ps	17.08mV
Accumulated Eye		Lower	-69.17mV	-941.61s	22.42pt	25.57pt	27.70ps	547.911	18.82p	s 13.57ps	21.35mV
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Figure 14: PAM4 Analysis

Automotive MultiGBASE-T1 uses four-level Pulse Amplitude Modulation (PAM4) for physical layer transmission since PAM4 signaling needs half the bandwidth as NRZ for the same data rate. However the 4 levels of PAM4 introduce additional complexity in signaling and place new demands on the test methodology. The PAM4 analysis tool offers several measurement and visualization capabilities to make validating PAM4 designs significantly more efficient.

PAM4 Analysis

- Enhanced software clock recovery offers the industry's most robust clock recovery capability even from heavily impaired signals.
- Integrated receiver equalization: Apply CTLE, FFE and DFE equalization to the acquired waveform to open a closed eye. Model different types of receiver settings to perform what-if analysis.
- Configurable Bessel-Thomson filter offers the flexibility to tune bandwidth of the measurement receiver, either manually or automatically, based on detected data rate.
- Waveform filter enables embed or de-embed test fixtures or channel models.

PAM4 Measurements

- Jitter measurement and eye analysis: Full Characterization of the PAM4 eyes to support standard based and debug analysis.
- Rise and fall times for all 12 PAM4 transitions offer the capability to analyze each transition type in the PAM4 signal.
- Symbol and bit error detector: Accumulate SER and BER over multiple acquisition cycles.

Plots and reports

 Comprehensive plots enable in-depth analysis. HTML report captures all the relevant setup configuration, measurement test results, and plot in single file that is easy to read and share. Measurement results across multiple acquisitions can be exported to a consolidated CSV file for easy multi-run analysis.

Automotive Ethernet Decoder for 100BASE-T1 (Option SR-AUTOETH1)



Figure 15: 100BASE-T1 Protocol decode

Decode and display Automotive Ethernet data in a protocol-aware view with the characters and names that are familiar from the standard such as the ordered sets: SOF, Electrical Idle, and EOF.

User can now feed the output of directional coupler to Tektronix Oscilloscope for time domain view. SR-AUTOETH1 100BASE-T1 protocol decode software runs on DPO70000SX and MSO/DPO70000 Series oscilloscopes and easily decodes PAM3-encoded 100BASET1 signal. This enables engineers to quickly understand the protocol activity between the ECUs. A time-correlated event table view with waveform allows for quickly searching through events of interest simultaneously.

Key Feautures

- Decodes PAM3 encoded 100BASE-T1 signals.
- Decodes Send_N mode packets without any training sequence.
- · Validate FCS and reports error packets in red color.
- Display the time stamp, packet type, IP source and destination address, decoding of the payload.
- Detail view correlates the decoded packets with waveform using a bus diagram.
- · Separately display Master and Slave packets.
- Export the decoded data in CSV or TXT file format.
- Report generation.

Ordering Information

Standard	Compliance Test	Instrument	Model number
Multigigabit Ethernet	Droop, Linearity, Dj and Rj Jitter,	Oscilloscope with min bandwidth of;	DPO70000 SX/DX series
	Power Spectral Density, Clock	4GHz bandwidth for 2.5Gbps,	
		8GHz bandwidth for 5Gbps,	
		13GHz bandwidth for 10Gbps	
	MDI Return Loss	Vector Network Analyzer with min 4GHz	3 rd Party VNA
1000BASE-T1	Droop, Jitter, Power Spectral Density, Clock frequency, Peak Differential output	Oscilloscope with min 2 GHz bandwidth	DPO70000 C/SX/DX series, MSO5/6B series
	Distortion Test	2 channel Function generators with min bandwidth of 125 MHz	AFG31000 series or AWG5200
	MDI Return Loss	AWG or Vector Network Analyzer	AWG5200 with Oscilloscope or 3 rd Party VNA
	MDI Mode conversion	Vector Network Analyzer	3 rd Party VNA
100BASE-T1	Droop, Jitter, Power Spectral Density, Clock frequency, Peak Differential output, Common mode emission	Oscilloscope with min 1 GHz bandwidth	DPO70000 C/SX/DX series, MSO5/6B series
	Distortion Test	2 channel Function generators with min bandwidth of 25 MHz	AFG31000 series
	MDI Return loss	AFG(125 MHz) or Vector Network Analyzer	AFG with Oscilloscope or 3 rd Party VNA
	MDI Mode conversion	Vector Network Analyzer	3 rd Party VNA

Software option

Standard	Compliance Test	Option	Description
MultiGBASE-T1	802.3ch Transmitter Compliance	AUTOEN10G	TekExpress Automotive Ethernet - MultiGBASE-T1 Compliance Solution(Requires Opt. DJA)
		DPO-UP AUTOEN10G	TekExpress Automotive Ethernet - MultiGBASE-T1 Compliance Solution(Requires Opt. DJA); Upgrade
		DPOFL-AUTOEN10G	TekExpress Automotive Ethernet - MultiGBASE-T1 Compliance Solution(Requires Opt. DJA); Floating
Table continued			

Standard	Compliance Test	Option	Description
100/1000BASE-T1 IEEE and Open Alliance PMATransmitter compliance	IEEE and Open Alliance PMATransmitter compliance	BRR	TekExpress Automotive Ethernet Compliance
	DPO-UP BRR	TekExpress Automotive Ethernet Compliance; Upgrade	
		DPOFL-BRR	TekExpress Automotive Ethernet Compliance; Floating
100BASE-T1	Protocol decode	SR-AUTOETH1	Automotive Ethernet 100BASE-T1 Protocol decode

Pre-requisite Software

Standard	Option	Description
MultiGBASE-T1	DJA	Advance Jitter Analysis (Order preinstalled on a new oscilloscope)

Optional Software

Standard	Option	Description
MultiGBASE-T1	PAM4	PAM4 Transmitter Analysis
Low Speed Protocol decode	SR-AUTO	CAN, LIN, FlexRay serial bus trigger and decode

MDI Return Loss with AWG/AFG Method

Standard	Model Number	Description
1000BASE-T1	AWG5202 with opt 250, 2 HV	Tektronix AWG5200 with high amplitude DC coupled with output option
	TDP3500 (2 nos)	3.5 GHz Differential Probe with TekVPI™ Probe Interface s (require TCA-VPI50 adapter)
100BASE-T1	AFG31152	1 μHz to 150 MHz sine wave, 2-channel arbitrary function generator
	TDP1500 (2 nos)	1.5 GHz Differential Probe with TekVPI™ Probe Interface s (require TCA-VPI50 adapter)

Probe

Standard	Model Number	Description
MultiGBASE-T1 (Optional)	P7700 series	TriMode probe with TekFlex connector technology
	P77C292MM	SMA Coaxial adapter with TekFlex connector technology, 20 GHz
	TDP3500	3.5 GHz Differential Probe with TekVPI™ Probe Interface s (require TCA-VPI50 adapter), for clock measurement
1000BASE-T1	TDP3500	3.5 GHz Differential Probe with TekVPI™ Probe Interfaces (require TCA-VPI50 adapter)
Table continued		

Standard	Model Number	Description
100BASE-T1	TDP1500	1.5 GHz Differential Probe with TekVPI™
		Probe Interfaces (require TCA-VPI50 adapter)

Accessory

Standard	Accessory	Part number	Use case
MultiGBASE-T1	Multigigabit Ethernet Fixture	PCB S3401 SB 396373 ¹	PMA Tx Compliance Measurement
MultiGBASE-T1	Matched Pair SMA cable		PMA Tx Compliance Measurement
100/1000BASE-T1	Fixture	TF-XGBT	PMA Tx Compliance Measurement
100/1000BASE-T1	Clock Divider unit	TF-BRR-CFD	Distortion test
100/1000BASE-T1	Fixture	02K3E6 K00S3 387390 ¹ 02K3E6 S00S3 387391 ¹ 02S3E6 S00S3 387392 ¹	Mode conversion and Return loss fixture with Rosenberger H-MTD connector
		02S3E6 K00S3 387393 ¹	
100BASE-T1	Directional Coupler	DCDP for H-MTD ¹	Protocol decode fixture with Rosenberger H-MTD connector
100BASE-T1	Power splitter	Mini circuit Z99SC-62 ¹	Common Mode emission test
100/1000BASE-T1	Two pairs of 50 Ω high-quality SMA or coaxial cables		AFG or AWG signal sources (AFG based Return loss)
100/1000BASE-T1	One 50 Ω high-quality coaxial cable		AFG or AWG signal source, for marker output (AFG based Return loss)
100/1000BASE-T1	Two 50 Ω high-quality coaxial cables		clock divider Input (distortion test)
100/1000BASE-T1	One 50 Ω high-quality SMA cable		clock divider Input (distortion test)



Tektronix is registered to ISO 9001 and ISO 14001 by SRI Quality System Registrar.



Product(s) complies with IEEE Standard 488.1-1987, RS-232-C, and with Tektronix Standard Codes and Formats.



Product Area Assessed: The planning, design/development and manufacture of electronic Test and Measurement instruments.

¹ 3rd Party items

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* European toll-free number. If not accessible, call: +41 52 675 3777

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